MOSFET – Power, Dual, N-Channel with Integrated Schottky, SO8FL

30 V, High Side 18 A / Low Side 30 A

Features

- Co-Packaged Power Stage Solution to Minimize Board Space
- Low Side MOSFET with Integrated Schottky
- Minimized Parasitic Inductances
- Optimized Devices to Reduce Power Losses
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

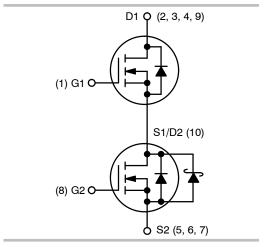
- DC-DC Converters
- System Voltage Rails
- Point of Load



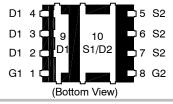
ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
Q1 Top FET	6.5 mΩ @ 10 V	10 4
30 V	10 mΩ @ 4.5 V	18 A
Q2 Bottom	2.35 m Ω @ 10 V	30 A
FET 30 V	3.5 mΩ @ 4.5 V	30 A



PIN CONNECTIONS



MARKING DIAGRAM



DFN8 CASE 506BX



4901NF = Specific Device Code

A = Assembly Location

Y = Year
W = Work Week
ZZ = Lot Traceability

ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 5 of this data sheet.

MAXIMUM RATINGS ($T_J = 25^{\circ}C$ unless otherwise stated)

Parameter				Symbol	Value	Unit
Drain-to-Source Voltage			Q1	V _{DSS}	30	V
Drain-to-Source Voltage			Q2			
Gate-to-Source Voltage			Q1	V _{GS}	±20	V
Gate-to-Source Voltage	Q2					
Continuous Drain Current R _{0JA} (Note 1)		T _A = 25°C	Q1	I _D	13.5	
		T _A = 85°C			9.7	1 .
		T _A = 25°C	Q2		23.4	A
		T _A = 85°C	1		16.9	
Power Dissipation R _{0JA} (Note 1)		T _A = 25°C	Q1	P _D	1.90	W
			Q2		2.07	
Continuous Drain Current $R_{\theta JA} \le 10 \text{ s (Note 1)}$		T _A = 25°C	Q1	I _D	18.2	
		T _A = 85°C	1		13.1	1
	Steady	T _A = 25°C	Q2		30.3	A
	State	T _A = 85°C			21.8	
Power Dissipation $R_{\theta JA} \le 10 \text{ s (Note 1)}$		T _A = 25°C	Q1	P _D	3.45	W
			Q2		3.45	
Continuous Drain Current R _{0JA} (Note 2)		T _A = 25°C	Q1	I _D	10.3	
		T _A = 85°C	1		7.4	1
		T _A = 25°C	Q2		17.9	A
		T _A = 85°C			12.9	
Power Dissipation R _{0JA} (Note 2)		T _A = 25 °C	Q1	P _D	1.10	W
			Q2		1.20	
Pulsed Drain Current		T _A = 25°C	Q1	I _{DM}	60	Α
		t _p = 10 μs	Q2		100	
Operating Junction and Storage Temperature			Q1	T _J , T _{STG}	-55 to +150	°C
			Q2			
Source Current (Body Diode)			Q1	I _S	3.4	Α
			Q2		4.9	1
Drain to Source dV/dt			•	dV/dt	6	V/ns
Single Pulse Drain-to-Source Avalanche Energy (T		24 A	Q1	EAS	28.8	mJ
= 50 V, V_{GS} = 10 V, I_L = XX A_{pk} , L = 0.1 mH, R_G = 28	5 Ω)	48 A	Q2	EAS	115	1
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)				T _L	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

^{1.} Surface-mounted on FR4 board using 1 sq-in pad, 2 oz Cu.

^{2.} Surface-mounted on FR4 board using the minimum recommended pad size of 100 $\mbox{mm}^2.$

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	FET	Symbol	Value	Unit
Junction-to-Ambient - Steady State (Note 3)	Q1	$R_{\theta JA}$	65.9	
	Q2		60.5	
Junction-to-Ambient - Steady State (Note 4)	Q1	R_{\thetaJA}	113.2	0000
	Q2		104	°C/W
Junction-to-Ambient – (t ≤ 10 s) (Note 3)	Q1	R_{\thetaJA}	36.2	
	Q2		36.2	

ELECTRICAL CHARACTERISTICS (T₁ = 25°C unless otherwise specified)

Parameter	FET	Symbol	Test Co	ondition	Min	Тур	Max	Unit
OFF CHARACTERISTICS	•							-
Drain-to-Source Break- down Voltage	Q1	V _{(BR)DSS}	V _{GS} = 0 V,	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$				V
	Q2		V _{GS} = 0 V ₃	I _D = 1 mA	30			1
Drain-to-Source Break- down Voltage Temperature Coefficient	Q1	V _{(BR)DSS}				18		mV / °C
	Q2	/ I J				15		
Zero Gate Voltage Drain	Q1	I _{DSS}	V _{GS} = 0 V,	T _J = 25°C			1	μΑ
Current			$V_{DS} = 24 \text{ V}$	T _J = 125°C			10	
	Q2		V _{GS} = 0 V, V _{DS} = 24 V	T _J = 25°C			500	
Gate-to-Source Leakage	Q1	I _{GSS}	V _{GS} = 0 V, VDS = ±20 V				±100	nA
Current	Q2						±100	1
ON CHARACTERISTICS (No	te 5)							
Gate Threshold Voltage	Q1	V _{GS(TH)}	$V_{GS} = V_{DS}$,	I _D = 250 μA	1.2		2.2	V
		1			4.0			1

Gate Threshold Voltage	Q1	V _{GS(TH)}	$V_{GS} = V_{DS}$	I _D = 250 μA	1.2		2.2	V
	Q2				1.2		2.2	
Negative Threshold Temperature Coefficient	Q1	V _{GS(TH)} / T _J				4.5		mV / °C
ature Coefficient	Q2	IJ				4.0		-0
Drain-to-Source On Resist-	Q1	R _{DS(on)}	V _{GS} = 10 V	I _D = 10 A		5.2	6.5	
ance			V _{GS} = 4.5 V	I _D = 10 A		8.0	10	~ 0
	Q2		V _{GS} = 10 V	I _D = 20 A		1.9	2.35	mΩ
			V _{GS} = 4.5 V	I _D = 20 A		2.8	3.5	
Forward Transconductance	Q1	9FS	V _{DS} = 1.5 \	V, I _D = 10 A		28		S
	Q2					45		

^{3.} Surface-mounted on FR4 board using 1 sq-in pad, 2 oz Cu.
4. Surface-mounted on FR4 board using the minimum recommended pad size of 100 mm².

^{5.} Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.
6. Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	FET	Symbol	Test Condition	Min	Тур	Max	Unit	
CHARGES, CAPACITANCE	S & GATE	RESISTANC	E	•	•			
	Q1				1150			
Input Capacitance	Q2	C _{ISS}	C _{ISS}		2950			
Output Capacitance	Q1	_			360		1 _	
Output Capacitance	Q2	C _{OSS}	$V_{GS} = 0 \text{ V, f} = 1 \text{ MHz, V}_{DS} = 15 \text{ V}$		1100		pF	
	Q1	_			105		1	
Reverse Capacitance	Q2	C _{RSS}			82			
T. 10 1 01	Q1				9.7			
Total Gate Charge	Q2	$Q_{G(TOT)}$			20			
reshold Gate Charge	Q1				1.1			
Threshold Gate Charge	Q2	Q _{G(TH)}	.,		2.7		nC	
0.1.1.0.01	Q1		$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 10 \text{ A}$		3.3			
Gate-to-Source Charge	Q2	Q_{GS}			7.3			
	Q1				3.7			
Gate-to-Drain Charge	Q2	Q_{GD}			5.3			
Total Gate Charge	Q1				19.1		nC	
	Q2	Q _{G(TOT)}	$Q_{G(TOT)}$ $V_{GS} = 10 \text{ V}, V_{DS} = 15 \text{ V}; I_D = 10 \text{ A}$		42.7			
SWITCHING CHARACTERIS	STICS (No	te 6)						
T O. D.L. T	Q1				9.0			
Turn-On Delay Time	Q2	t _{d(ON)}			14		1	
Dia a Tima	Q1				15		1	
Rise Time	Q2	t _r	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V},$		16			
T Of Delevi Time	Q1		$I_D = 10 \text{ A}, R_G = 3.0 \Omega$		14		ns -	
Turn-Off Delay Time	Q2	t _{d(OFF)}			25			
Fall Time	Q1				4.0			
Fall Time	Q2	t _f			7.0		1	
SWITCHING CHARACTERIS	STICS (No	te 6)						
T O. D.I. T	Q1				6.0			
Turn-On Delay Time Q2 Rise Time Q1 Q2 Q2	Q2	t _{d(ON)}			10		1	
	Q1				14		1	
	t _r	Ves = 10 V. Vps = 15 V.		15				
T O"Dala Tana	Q1		V_{GS} = 10 V, V_{DS} = 15 V, I_D = 10 A, R_G = 3.0 Ω		17		ns	
Turn-Off Delay Time	Q2	t _{d(OFF)}			32		1	
	Q1				3.0		1	
Fall Time	Q2 t _f			5.0		1		

^{5.} Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
6. Switching characteristics are independent of operating junction temperatures.

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	FET	Symbol	Test Co	ondition	Min	Тур	Max	Unit
DRAIN-SOURCE DIODE CH	ARACTE	RISTICS					•	
	0.4		V _{GS} = 0 V,	T _J = 25°C		0.75	1.0	
Farmend Vallage	Q1	V	$V_{GS} = 0 V$, $I_S = 3 A$	T _J = 125°C		0.62		.,
Forward Voltage	Q2	V_{SD}	V _{GS} = 0 V,	T _J = 25°C		0.45	0.70	V
	Q2		$V_{GS} = 0 V$, $I_S = 2 A$	T _J = 125°C		0.37		
D	Q1			•		23		
Reverse Recovery Time	Q2	t _{RR}				40		
Charge Time	Q1	1-	1			12		
	Q2	- ta				21		ns
Discharge Time	Q1	11.	$V_{GS} = 0 \text{ V, } a_{IS}/a_{t} =$	$V, d_{IS}/d_t = 100 \text{ A/}\mu\text{s}, I_S = 3 \text{ A}$		11		
	Q2	tb			19			
D D Ol	Q1		1			12		
Reverse Recovery Charge	Q2	Q_{RR}			40		nC	
PACKAGE PARASITIC VALU	ES							
On the last of the con-	Q1					0.38		
Source Inductance	Q2	L _S				0.65		nH
B : 1 1 .	Q1					0.054		
Drain Inductance	Q2	L _D				0.007		nH
Gate Inductance	Q1		I _A =	T _A = 25°C		1.5		T
	Q2	L _G				1.5		nH
Oala Basislana	Q1		1			0.8		
Gate Resistance	Q2	R _G				0.8		Ω

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMFD4901NFT1G	DFN8 (Pb-Free)	1500 / Tape & Reel
NTMFD4901NFT3G	DFN8 (Pb-Free)	5000 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

^{5.} Pulse Test: pulse width \leq 300 μ s, duty cycle \leq 2%.
6. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS - Q1

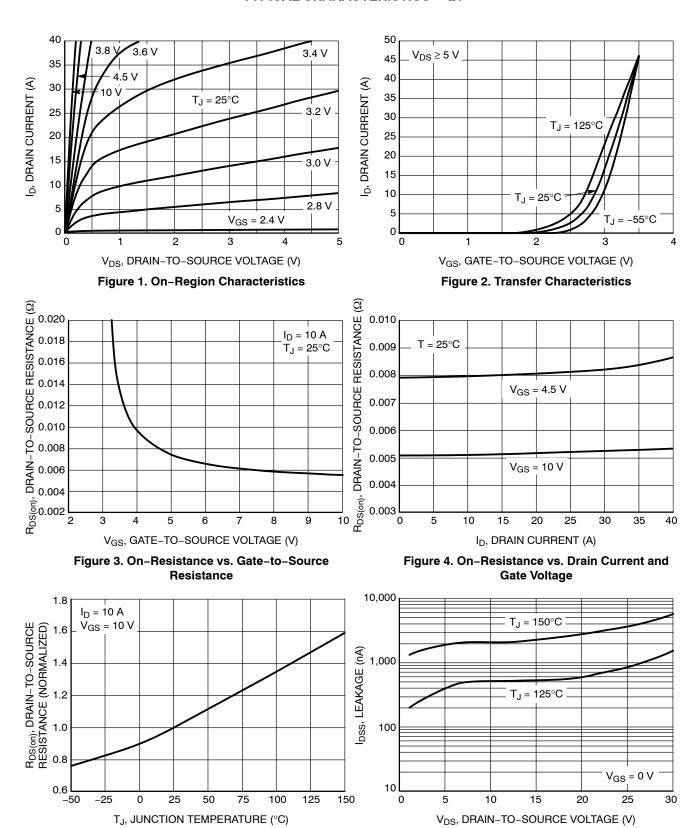


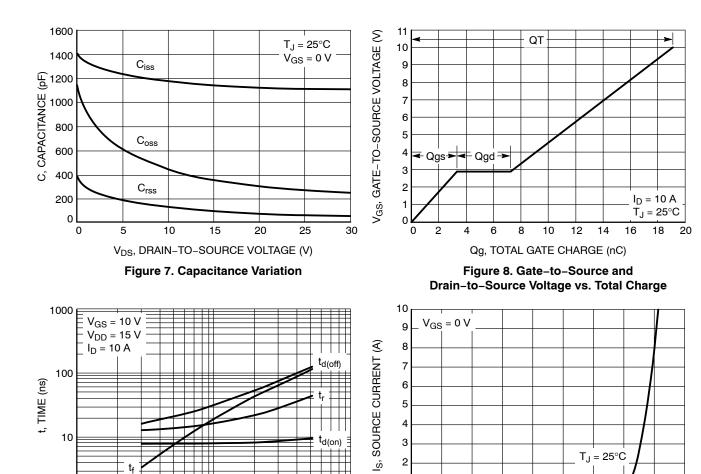
Figure 6. Drain-to-Source Leakage Current

vs. Voltage

Figure 5. On-Resistance Variation with

Temperature

TYPICAL CHARACTERISTICS - Q1



1

0.0

0.1

0.2

0.3

 $\label{eq:RG} \textbf{R}_{\textbf{G}}, \, \textbf{GATE} \, \, \textbf{RESISTANCE} \, \, (\Omega)$ Figure 9. Resistive Switching Time Variation vs. Gate Resistance

10

1

 $\label{eq:VSD} V_{SD}, \text{SOURCE-TO-DRAIN VOLTAGE (V)}$ Figure 10. Diode Forward Voltage vs. Current

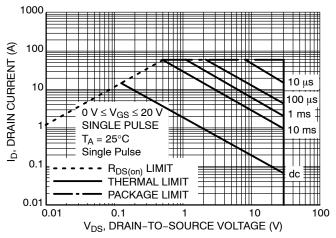
0.5

0.6

0.7

8.0

0.4



100

Figure 11. Maximum Rated Forward Biased Safe Operating Area

TYPICAL CHARACTERISTICS - Q1

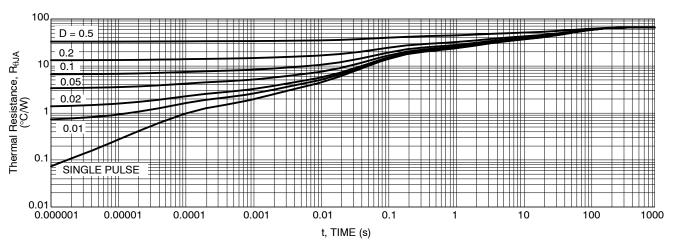


Figure 12. Thermal Response

TYPICAL CHARACTERISTICS - Q2

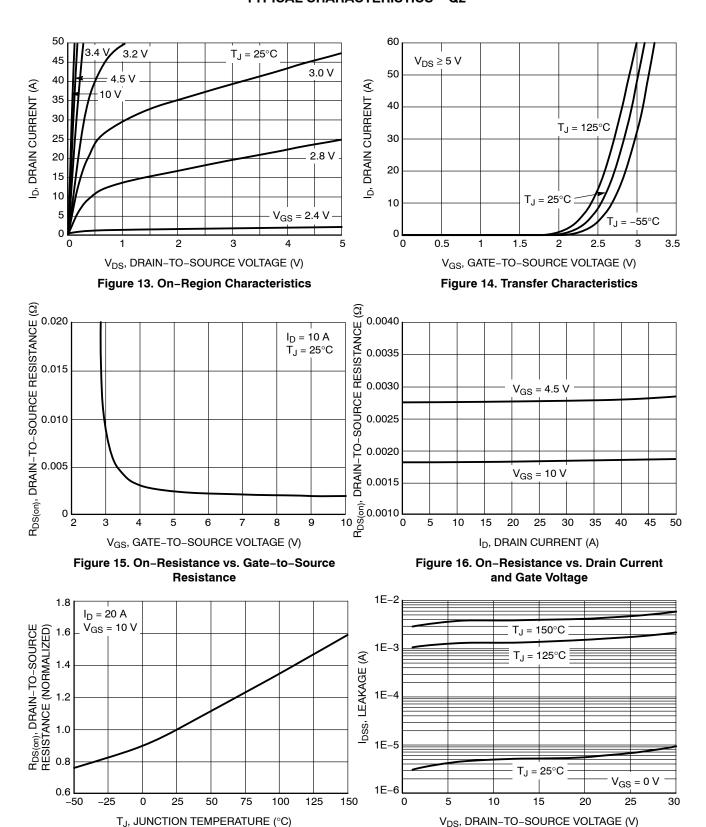


Figure 18. Drain-to-Source Leakage Current

vs. Voltage

Figure 17. On-Resistance Variation with

Temperature

TYPICAL CHARACTERISTICS - Q2

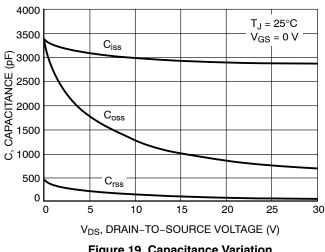


Figure 19. Capacitance Variation

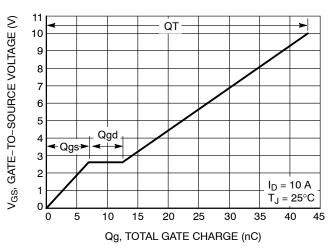


Figure 20. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

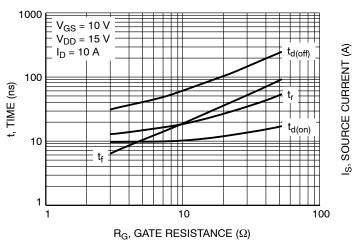


Figure 21. Resistive Switching Time Variation vs. Gate Resistance

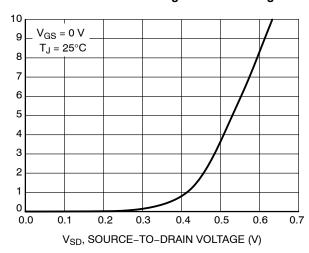


Figure 22. Diode Forward Voltage vs. Current

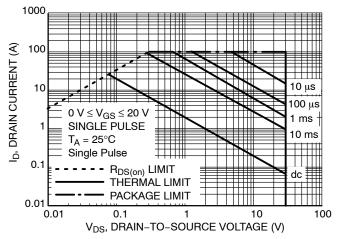


Figure 23. Maximum Rated Forward Biased **Safe Operating Area**

TYPICAL CHARACTERISTICS - Q2

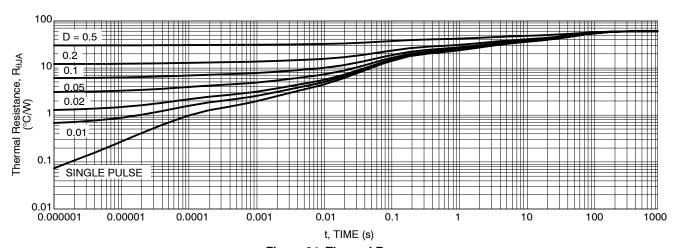
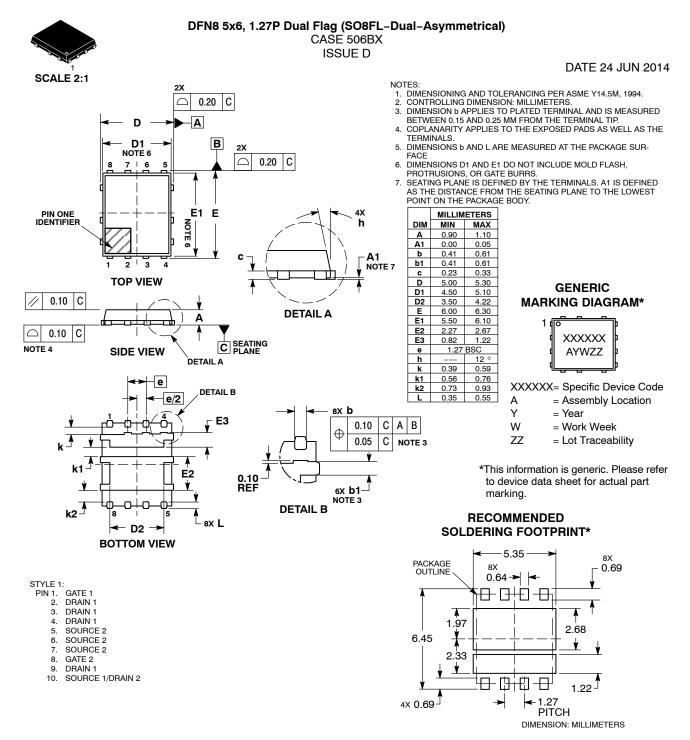


Figure 24. Thermal Response



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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